



RELIABILITY REPORT
FOR
MAX7412EUA+
PLASTIC ENCAPSULATED DEVICES

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MAXIM INTEGRATED PRODUCTS

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Conclusion

The MAX7412EUA+ successfully meets the quality and reliability standards required of all Maxim products. In addition, Maxim's continuous reliability monitoring program ensures that all outgoing product will continue to meet Maxim's quality and reliability standards.

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I. Device Description

A. General

The MAX7408/MAX7411/MAX7412/MAX7415 5th-order, lowpass, elliptic, switched-capacitor filters (SCFs) operate from a single +5V (MAX7408/MAX7411) or +3V (MAX7412/MAX7415) supply. The devices draw only 1.2mA of supply current and allow corner frequencies from 1Hz to 15kHz, making them ideal for low-power post-DAC filtering and anti-aliasing applications. They can be put into a low-power mode, reducing supply current to 0.2 μ A. Two clocking options are available: self-clocking (through the use of an external capacitor) or external clocking for tighter cutoff-frequency control. An offset-adjust pin allows for adjustment of the DC output level. The MAX7408/MAX7412 deliver 53dB of stopband rejection and a sharp rolloff with a transition ratio of 1.6. The MAX7411/MAX7415 achieve a sharper rolloff with a transition ratio of 1.25 while still providing 37dB of stop-band rejection. Their fixed response limits the design task to selecting a clock frequency.

II. Manufacturing Information

A. Description/Function:	5th Order, Lowpass, Elliptic, Switched-Capacitor Filters
B. Process:	C6
C. Number of Device Transistors:	1396
D. Fabrication Location:	Taiwan
E. Assembly Location:	Philippines, Thailand, Malaysia
F. Date of Initial Production:	October 16, 1998

III. Packaging Information

A. Package Type:	3x3 mm 8L UMAX
B. Lead Frame:	Copper
C. Lead Finish:	100% matte Tin
D. Die Attach:	Conductive
E. Bondwire:	Au (1.3 mil dia.)
F. Mold Material:	Epoxy with silica filler
G. Assembly Diagram:	#05-0201-0128 / B
H. Flammability Rating:	Class UL94-V0
I. Classification of Moisture Sensitivity per JEDEC standard J-STD-020-C	1
J. Single Layer Theta Ja:	221°C/W
K. Single Layer Theta Jc:	42°C/W
L. Multi Layer Theta Ja:	206.3°C/W
M. Multi Layer Theta Jc:	42°C/W

IV. Die Information

A. Dimensions:	59 X 81 mils
B. Passivation:	Si ₃ N ₄ /SiO ₂ (Silicon nitride/ Silicon dioxide)
C. Interconnect:	Al with Ti/TiN Barrier
D. Backside Metallization:	None
E. Minimum Metal Width:	0.6 microns (as drawn)
F. Minimum Metal Spacing:	0.6 microns (as drawn)
G. Bondpad Dimensions:	
H. Isolation Dielectric:	SiO ₂
I. Die Separation Method:Wafer	Saw

V. Quality Assurance Information

- A. Quality Assurance Contacts: Richard Aburano (Manager, Reliability Engineering)
Don Lipps (Manager, Reliability Engineering)
Bryan Preeshl (Vice President of QA)
- B. Outgoing Inspection Level: 0.1% for all electrical parameters guaranteed by the Datasheet.
0.1% For all Visual Defects.
- C. Observed Outgoing Defect Rate: < 50 ppm
- D. Sampling Plan: Mil-Std-105D

VI. Reliability Evaluation

A. Accelerated Life Test

The results of the biased (static) life test are shown in Table 1. Using these results, the Failure Rate (λ) is calculated as follows:

$$\lambda = \frac{1}{\text{MTTF}} = \frac{1.83}{192 \times 4340 \times 80 \times 2} \quad (\text{Chi square value for MTTF upper limit})$$

(where 4340 = Temperature Acceleration factor assuming an activation energy of 0.8eV)

$$\lambda = 13.7 \times 10^{-9}$$

$$\lambda = 13.7 \text{ F.I.T. (60\% confidence level @ 25}^\circ\text{C)}$$

The following failure rate represents data collected from Maxim's reliability monitor program. Maxim performs quarterly life test monitors on its processes. This data is published in the Reliability Report found at <http://www.maxim-ic.com/qa/reliability/monitor>. Cumulative monitor data for the C6 Process results in a FIT Rate of 0.90 @ 25C and 15.55 @ 55C (0.8 eV, 60% UCL)

B. E.S.D. and Latch-Up Testing (lot KR5AAX001 D/C 9822)

The AF16 die type has been found to have all pins able to withstand a HBM transient pulse of +/-2000V per Mil-Std 883 Method 3015.7. Latch-Up testing has shown that this device withstands a current of +/-250mA.

Table 1
Reliability Evaluation Test Results

MAX7412EUA+

TEST ITEM	TEST CONDITION	FAILURE IDENTIFICATION	SAMPLE SIZE	NUMBER OF FAILURES	COMMENTS
Static Life Test (Note 1)	Ta = 135°C Biased Time = 192 hrs.	DC Parameters & functionality	80	0	N/A

Note 1: Life Test Data may represent plastic DIP qualification lots.